

<b>Notice of References Cited</b>	Application/Control No. 10/743,760	Applicant(s)/Patent Under Reexamination TANAKA	
	Examiner Jason T. Whipkey	Art Unit 2622	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,614,975 A	09-1986	Kaite, Osamu	348/354
*	B	US-6,493,027 B2	12-2002	Ohta et al.	348/220.1
*	C	US-2003/0142880 A1	07-2003	Hyodo, Manabu	382/274
*	D	US-2003/0174230 A1	09-2003	Ide et al.	348/345
*	E	US-6,785,469 B1	08-2004	Ide et al.	396/121
*	F	US-6,919,927 B1	07-2005	Hyodo, Manabu	348/333.02
*	G	US-6,975,361 B2	12-2005	Kamon et al.	348/375
*	H	US-6,977,687 B1	12-2005	Suh, Inh-Seok	348/345
*	I	US-7,034,881 B1	04-2006	Hyodo et al.	348/333.12
*	J	US-7,171,625 B1	01-2007	Sacchi, Cristiano	715/754
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.